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## **BEST AVAILABLE COPY**

Sheet 1 of 2 FORM PTO-1449 ATTY.DOCKET NO. SERIAL NO. 7537.29 09/298,245 INFORMATION DISCLOSURE APPLICANTS CITATION Jau-Fei Chen FILING DATE GROUP April 23, 1999 1615 EXAMINE TEADER **U.S. PATENT DOCUMENTS** UMENT NUMBER **CLASS** SUBCLASS FILING DATE DATE NAME 12/15/94 5,578,312 11/26/96 Parrinello 424 401 Α6 Α8 **FOREIGN PATENT DOCUMENTS** TRANSLATION \*EXAMINER **DOCUMENT NUMBER** INITIAL DATE COUNTRY **CLASS SUBCLASS** <u>YES</u> <u>NO</u> Х W0 96 27383 A; 5 . . PCT (French language document) English abstract of Korean patent document No. 97 032 503 A Korea English abstract of South African patent document No. ZA 6 000 062 A South Africa English abstract of Japan Japanese patent document No. 58 067151 A English abstract of Spanish Spain ()/A patent document No. 2 041 218 B 27 03 189 A Х Germany J.201 English abstract of Japan Japanese patent document No. 09 249576 A English abstract of Japan Japanese patent document No. 61 085324 A English abstract of Chinese China patent document No. 1 076 624 A English abstract of Chinese China patent document No. 1 090 988 A DATE CONSIDERED EXAMINER 9.9.01

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OCT 1 8 2000 Sheet 2 of 2 EXAMINER DOCUMENT FADERS FOR A PARENT OF THE TRANSLATION DOCUMENT NUMBER **CLASS SUBCLASS** DATE COUNTRY <u>YES</u> <u>NO</u> Japan Japanese patent document No. 63 116669 A Japan English abstract of Japanese patent document No. 07 267 977 A English abstract of Chinese patent document No. 1,211\* 403 A China 58 67151 Japan 9 249576 1 Japan 61 85324 Japan 1076624 A China 1090988 A -China 63 116669 : Japan 7 267977' -Japan х 1211403 A China 97 032 503A / Korea English abstract of Japanese patent document No. 10072338 2 041 218 B<sub>7</sub> Spain Х

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